

COPY OF ART CITED BY APPLICANT (PTO-1449) NOV 23 2004 U.S. PATENT OFFICE		ATTY. DOCKET NO. K-0609		APPLN. SERIAL NO. 10/776,198			
		APPLICANT(S) Seung Kiu LEE					
		FILING DATE February 12, 2004		GROUP			
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE	
AS	6,280,034 B1	8/28/2001	Brennesholtz	353	20	7/30/1999	
U.S. PATENT APPLICATION PUBLICATIONS							
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	FILING DATE	
AS	2002/0176146 A1	11/28/2002	De Vaan	359	242	5/20/2002	
U.S. PATENT APPLICATIONS							
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS		
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
AS	WO 01/33865	5/10/2001	WIPO			Yes	No
AS	WO 01/55774	8/2/2001	WIPO			XX	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)							
EXAMINER				DATE CONSIDERED			
[Signature]				8/31/2005			

**EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

	*APPLN. NO	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
AS	2001-142144	5/25/2001	JAPAN (Full Japanese Text)			Abst. only	

8/31/2005

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.